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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/522,397	10/21/2005	Bernard Beaumont	15675P568	6314
8791 7590 07/10/2007 BLAKELY SOKOLOFF TAYLOR & ZAFMAN			EXAMINER	
1279 OAKME.	AD PARKWAY		CHAET, MARISSA W	
SUNNYVALE	, CA 94085-4040		ART UNIT	PAPER NUMBER
•			1722	
			MAIL DATE	DELIVERY MODE
			07/10/2007	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

		Application No.	Applicant(s)			
		10/522,397	BEAUMONT ET AL.			
Office	Action Summary	Examiner	Art Unit			
		Marissa W. Chaet	1722			
The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply						
WHICHEVER IS - Extensions of time ma after SIX (6) MONTHS - If NO period for reply it Failure to reply within Any reply received by	STATUTORY PERIOD FOR REPLY LONGER, FROM THE MAILING DAY be available under the provisions of 37 CFR 1.13 from the mailing date of this communication. It is specified above, the maximum statutory period with the set or extended period for reply will, by statute, the Office later than three months after the mailing ligustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION 16(a). In no event, however, may a reply be tin 11 apply and will expire SIX (6) MONTHS from 12 cause the application to become ABANDONE	N. nely filed the mailing date of this communication. (D. (35 U.S.C. § 133).			
Status						
1) Responsive	Responsive to communication(s) filed on					
,	This action is FINAL . 2b)⊠ This action is non-final.					
•	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is					
closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.						
Disposition of Claim	ıs					
4a) Of the a 5) ☐ Claim(s) 6) ☑ Claim(s) <u>1-</u> 7) ☐ Claim(s)	22 is/are pending in the application. bove claim(s) is/are withdrav is/are allowed. 22 is/are rejected is/are objected to are subject to restriction and/or	vn from consideration.				
Application Papers						
, ,	cation is objected to by the Examine					
10) \boxtimes The drawing(s) filed on <u>21 January 2005</u> is/are: a) \boxtimes accepted or b) \square objected to by the Examiner.						
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).						
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d). 11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.						
Priority under 35 U.	S.C. § 119					
12)⊠ Acknowledg a)⊠ All b)□ 1.□ Certi 2.□ Certi 3.⊠ Copi appli	gment is made of a claim for foreign Some * c) None of: fied copies of the priority documents fied copies of the priority documents es of the certified copies of the priorication from the International Bureau ched detailed Office action for a list	s have been received. s have been received in Applicat rity documents have been receive u (PCT Rule 17.2(a)).	ion No ed in this National Stage			
		·				
Attachment(s) .						
1) Notice of Reference		4) Interview Summary				
	son's Patent Drawing Review (PTO-948) ure Statement(s) (PTO/SB/08) ate <u>5/23/05, 8/4/05</u> .	Paper No(s)/Mail D 5) Notice of Informal F 6) Other:				

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DETAILED ACTION

Claim Rejections - 35 USC § 112

The following is a quotation of the second paragraph of 35 U.S.C. 112:

The specification shall conclude with one or more claims particularly pointing out and distinctly claiming the subject matter which the applicant regards as his invention.

Claim 19 is rejected under 35 U.S.C. 112, second paragraph, as being indefinite for failing to particularly point out and distinctly claim the subject matter which applicant regards as the invention. The claim does not further limit the invention. The claim does not set forth any limitation not already claimed.

Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 1. Claims 1-9, 12-13, 15, and 21-22 are rejected under 35 U.S.C. 102(b) as being anticipated by Motoki et al. (2002/0028564).
- 2. Regarding claim 1, Motoki discloses a process for making a GaN film starting from a substrate (10) by depositing GaN by vapor phase epitaxy, such that the GaN deposit comprising at least one vapor phase epitaxial lateral overgrowth step, and at least one ELO step is preceded by the etching of openings (12) in a previously deposited dielectric mask (11) and such that an

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asymmetry is introduced into the dislocations environment (14) during one of the ELO steps. See Fig. 4; para. 22-28.

- 3. Regarding claim 2, Motoki discloses an asymmetry induced by making openings with unequal geometry in the dielectric mask. See Fig. 2, 3; para. 318.
- 4. Regarding claim 3, Motoki discloses making openings in the dielectric mask that are adjacent, unequal, and asymmetric forming a basic pattern of a periodic network comprising at least 2 openings. See Fig. 2, 3; para. 318.
- 5. Regarding claim 4, Motoki discloses openings that are round, striped (rectangular), or other polygon shape. See Fig. 2, 3; para. 25-26.
- 6. Regarding claim 5, Motoki discloses a periodic network extending along the [10-10] axis. See Fig. 2; para. 28.
- 7. Regarding claim 6, Motoki discloses ELO steps that are made by HVPE. See para. 23.
- 8. Regarding claim 7, Motoki discloses ELP steps done along the C(0001), M(1-100) and A(11-20) planes. See para. 66.
- Regarding claims 8-9, Motoki discloses a GaAs or sapphire substrate.
 See para. 27.
- Regarding claim 12, Motoki discloses openings that are etched in a dielectric mask. See para. 27.
- 11. Regarding claim 13, Motoki discloses GaN base layer is made by HVPE. See para. 23.
- 12. Regarding claim 15, Motoki discloses a process comprising 2 ELO steps, the GaN deposition during the first step made in GaN zones located in the

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openings, and the GaN deposition during the second step leads to lateral overgrowth until coalescence. See Fig. 4(1)-(4); para. 323-329.

- 13. Regarding claim 21, Motoki discloses an optoelectronic component. See para. 9.
- 14. Regarding claim 22, Motoki discloses a laser diode made from GaN film. See para. 2.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

- (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 15. Claims 10-11 are rejected under 35 U.S.C. 103(a) as being unpatentable over Motoki et al. (2002/0028564) in view of Okuyama et al. (US 2002/0117677).
- 16. Regarding claim 10, Motoki does not disclose doping GaN. However, Okuyama discloses silicon and magnesium-doped GaN. See para. 3. Thus, it would have been obvious to one of ordinary skill in the art at the time of invention to modify Motoki to include magnesium-doped GaN, as suggested by Okuyama, to form a p-type cladding layer.
- 17. Regarding claim 11, Motoki does not disclose an isoelectric impurity.

 However, Okuyama discloses introducing Indium to GaN. See para. 200. Thus, it would have been obvious to one of ordinary skill in the art at the time of

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invention to modify Motoki to add Indium to GaN, as suggested by Okuyama, to form an active layer.

- 18. Claims 14, 16-17 are rejected under 35 U.S.C. 103(a) as being unpatentable over Motoki et al. (2002/0028564) in view of Beaumont et al. (US 6,802,902).
- 19. Regarding claim 14, Motoki discloses the formation of the GaN base layer comprising: deposition of SiN (para. 25), deposition of GaN buffer layer, high temperature annealing at about 1020°C, and deposition by epitaxy of GaN. See para. 323-329. Motoki does not disclose the thickness of the SiN. However, Beaumont discloses SiN film with a thickness of 1 angstrom, approximately equal to one atomic plane. See col. 8, lines 20-31. Thus, it would have been obvious to one of ordinary skill in the art at the time of invention to modify Motoki to include SiN thickness at the atomic level, as suggested by Beaumont, to avoid etching of the masks by expensive techniques.
- 20. Regarding claim 16-17, Motoki does not disclose growth rates. However, Beaumont discloses the first ELO step having a growth rate along the <0001> direction, and the second ELO step having a lateral growth rate greater than <0001> by adding magnesium. See col. 6, line 65 col. 7, line 20. Thus, it would have been obvious to one of ordinary skill in the art at the time of invention to modify Motoki to include add magnesium during ELO, as suggested by Beaumont, to act as a surfactant, favoring the adsorption of gallium on certain faces and preventing it on other faces.

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- 21. Claims 18-20 are rejected under 35 U.S.C. 103(a) as being unpatentable over Motoki et al. (2002/0028564).
- 22. Regarding claim 18, Motoki discloses openings being etched in a mask.

 However, it would have been obvious to one of ordinary skill in the art at the time of invention to etch openings into the substrate to be more efficient.
- 23. Regarding claim 19, Motoki does not disclose implementing the process for making GaN according to operation conditions. However, it would have been obvious to one of ordinary skill in the art at the time of invention to make GaN according to operation conditions for consistency purposes.
- 24. Regarding claim 20, Motoki discloses GaN film with a thickness of 200-600 micrometers. See para. 42. However, it would have been obvious to one of ordinary skill in the art at the time of invention to produce thinner film with a thickness of between 1-20 micrometers.

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Marissa W. Chaet whose telephone number is 571-272-8094. The examiner can normally be reached on Monday-Friday 8:30am-5:00pm EST.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Yogendra N. Gupta can be reached on 571-272-1316.

The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

MWC June 13, 2007

/Robert Kunemund/
Robert Kunemund
Primary Patent Examiner
TC 1700